

Notice of References Cited	Application/Control No. 09/977,994		Applicant(s)/Patent Under Reexamination NAGATA ET AL.	
	Examiner Jeffrey R. West		Art Unit 2857	Page 1 of 1

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	B	US-6,144,217	11-2000	Iwata et al.	326/27
	C	US-4,366,456	12-1982	Ueno et al.	333/173
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	M	US-			

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	U	60/190,704				
*	V	Nagata et al., "Measurements and Analyses of Substrate Noise Waveform in Mixed Signal IC Environment". Proceedings of the IEEE 1999 Custom Integrated Circuits Conference. May 1999.				
*	W	Mitra et al., "Substrate-Aware Mixed-Signal Macrocell Placement in WRIGHT". IEEE Journal of Solid-State Circuits. Vol. 30. No. 3, March 1995.				
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.